## FIGURE CAPTIONS

## Chapter 2

Table 2-1 Typical results of proposed accuracy improvement procedure for  $4\times0.24\times32\mu m^2$  SiGe at  $V_{BE}$ =0.82 V,  $V_{CE}$ =3 V,  $I_B$ =9.136  $\mu A$ , and  $I_C$ =1.516 mA. The initial value of  $R_{bi}|_{L}$ ,  $R_{bi}|_{H}$ ,  $C_{bci}$ , and  $C_{bcx}$  are 14.85  $\Omega$ , 17.31  $\Omega$ , 4.7897 fF, and 15.7303 fF, respectively. The extracted value of  $R_{bi}C_{bci}$ ,  $C_{\pi}$  and  $C_{bci}$ + $C_{bcx}$  are 82.91fsec, 410.31fF and 20.52fF, respectively.

## Chapter 4

Table 4-1 Bias at VBE=0.83V, VCE=3V (a) Extrinsic and substrate parameters extracted (b) Intrinsic parameters extracted with emitter length variation

Table 4-2 Bias at VBE=0.83V, VCE=3V (a) Extrinsic and substrate parameters extracted (b) Intrinsic parameters extracted with emitter width variation

Table 4-3 Bias at  $V_{BE}=0.83V$ ,  $V_{CE}=3V$  (a) Extrinsic and substrate parameters extracted (b) Intrinsic parameters extracted with emitter finger number variation

Table 4-4 Bias at VBE=0.83V, VCE=3V (a) Extrinsic and substrate parameters extracted (b) Intrinsic parameters extracted with cell number variation